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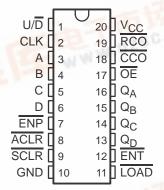
- 3-State Q Outputs Drive Bus Lines Directly
- Counter Operation Independent of 3-State Output
- Fully Synchronous Clear, Count, and Load
- Asynchronous Clear Is Also Provided
- Fully Cascadable
- Package Options Include Plastic Small-Outline (DW) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

description

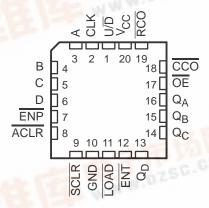
The SN74ALS568A decade counter and 'ALS569A binary counters are programmable, count up or down, and offer both synchronous and asynchronous clearing. All synchronous functions are executed on the positive-going edge of the clock (CLK) input.

The clear function is initiated by applying a low level to either asynchronous clear (\overline{ACLR}) or synchronous clear (\overline{SCLR}). Asynchronous (direct) clearing overrides all other functions of the device, while synchronous clearing overrides only the other synchronous functions. Data is loaded from the A, B, C, and D inputs by holding load (\overline{LOAD}) low during a positive-going clock transition. The counting function is enabled only when enable P (\overline{ENP}) and enable T (\overline{ENT}) are low and \overline{ACLR} , \overline{SCLR} , and \overline{LOAD} are high. The up/down (U/ \overline{D}) input controls the direction of the count. These counters count up when U/ \overline{D} is high and count down when U/ \overline{D} is low.

SN54ALS569A . . . J PACKAGE SN74ALS568A, SN74ALS569A . . . DW OR N PACKAGE (TOP VIEW)



SN54ALS569A . . . FK PACKAGE (TOP VIEW)



A high level at the output-enable (\overline{OE}) input forces the Q outputs into the high-impedance state, and a low level enables those outputs. Counting is independent of \overline{OE} . \overline{ENT} is fed forward to enable the ripple-carry output (\overline{RCO}) to produce a low-level pulse while the count is zero (all Q outputs low) when counting down or maximum (9 or 15) when counting up. The clocked carry output (\overline{CCO}) produces a low-level pulse for a duration equal to that of the low level of the clock when \overline{RCO} is low and the counter is enabled (both \overline{ENP} and \overline{ENT} are low); otherwise, \overline{CCO} is high. \overline{CCO} does not have the glitches commonly associated with a ripple-carry output. Cascading is normally accomplished by connecting \overline{RCO} or \overline{CCO} of the first counter to \overline{ENT} of the next counter. However, for very high-speed counting, \overline{RCO} should be used for cascading since \overline{CCO} does not become active until the clock returns to the low level.

The SN54ALS569A is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74ALS568A and SN74ALS569A are characterized for operation from 0°C to 70°C.



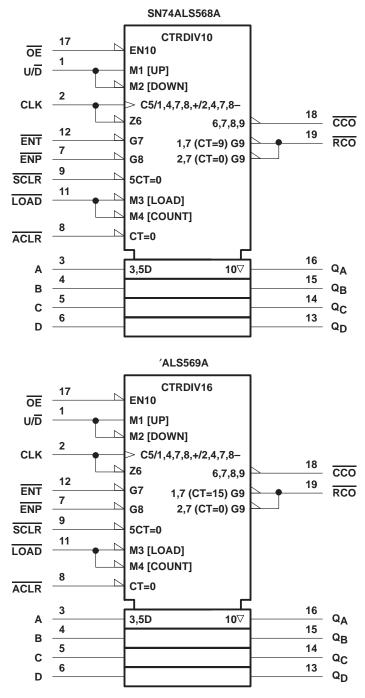
SN54ALS569A, SN74ALS568A, SN74ALS569A SYNCHRONOUS 4-BIT UP/DOWN DECADE AND BINARY COUNTERS WITH 3-STATE OUTPUTS SDAS229A – APRIL 1982 – REVISED JANUARY 1995

FUNCTION TABLE

			INPUTS					OPERATION
OE	ACLR	SCLR	LOAD	ENT	ENP	U/D	CLK	OPERATION
Н	Х	Х	Х	Χ	Х	Χ	Х	Q outputs disabled
L	L	X	Χ	Χ	X	Χ	X	Asynchronous clear
L	Н	L	X	Χ	X	Χ	\uparrow	Synchronous clear
L	Н	Н	L	Χ	X	Χ	\uparrow	Load
L	Н	Н	Н	L	L	Н	\uparrow	Count up
L	Н	Н	Н	L	L	L	\uparrow	Count down
L	Н	Н	Н	Н	Χ	Χ	Χ	Inhibit count
L	Н	Н	Н	Χ	Н	Χ	Χ	Inhibit count

SDAS229A - APRIL 1982 - REVISED JANUARY 1995

logic symbols†

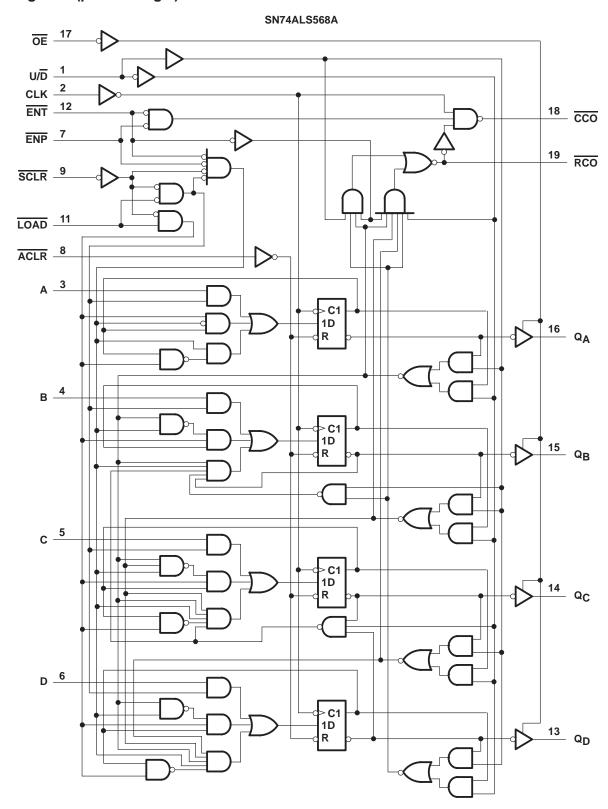


[†] These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



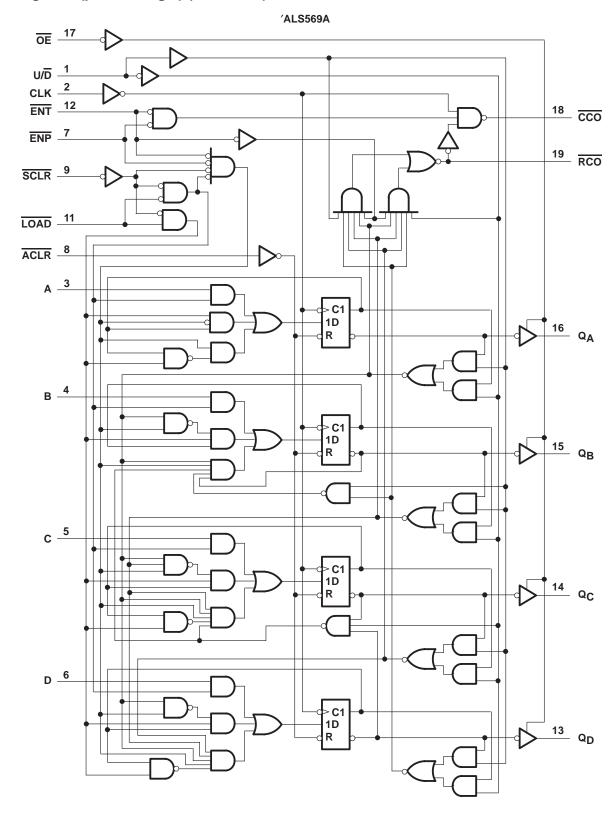
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logic diagrams (positive logic)



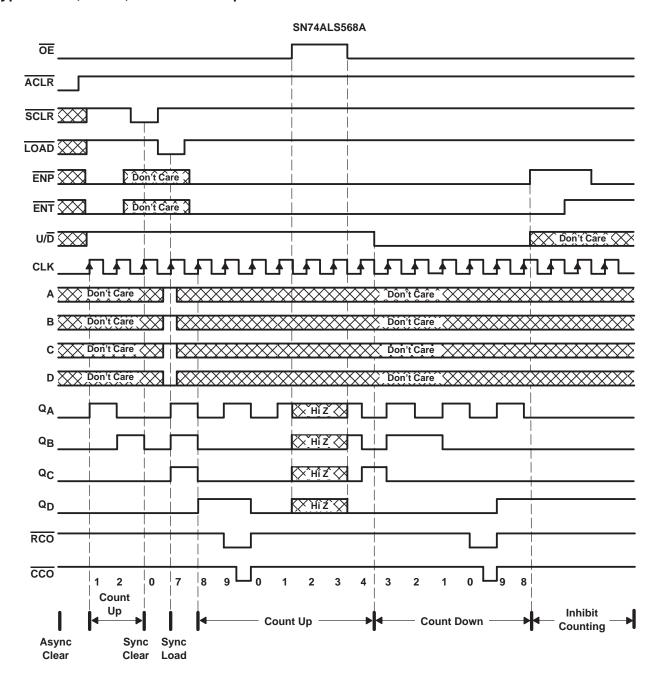
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logic diagrams (positive logic) (continued)



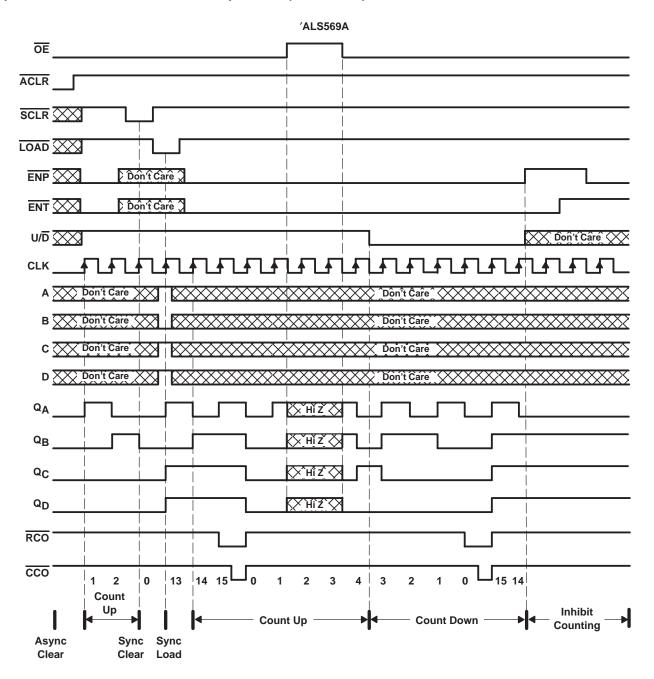
SDAS229A - APRIL 1982 - REVISED JANUARY 1995

typical load, count, and inhibit sequences



SDAS229A - APRIL 1982 - REVISED JANUARY 1995

typical load, count, and inhibit sequences (continued)



SDAS229A - APRIL 1982 - REVISED JANUARY 1995

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{CC}	7 V
Input voltage, V _I	7 V
Voltage applied to a disabled 3-state output	5.5 V
Operating free-air temperature range, T _A : SN54ALS569A	. −55°C to 125°C
SN74ALS568A, SN74ALS569A	0°C to 70°C
Storage temperature range	65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

				SN54ALS569A		SN74ALS568A SN74ALS569A			UNIT		
				MIN	NOM	MAX	MIN	NOM	MAX		
Vcc	Supply voltage			4.5	5	5.5	4.5	5	5.5	V	
VIH	High-level input voltage			2			2			V	
V _{IL}	Low-level input voltage					0.7			0.8	V	
1	High-level output current	Q outputs	Q outputs			-1			-2.6	mA	
ЮН		CCO and RCO				-0.4			-0.4	mA	
1	Lave lavel autout aumant	Q outputs				12			24	mA	
IOL	Low-level output current	CCO and RCO				4			8		
٤	Clock fraguency	SN74ALS568A					0		20	MHz	
^f clock	Clock frequency	'ALS569A		0		22	0		30	IVITZ	
	Pulse duration	ACLR or LOAD low		20			15				
t _W		SN74ALS568A	CLK high				25				
			CLK low				25			ns	
		′ALS569A	CLK high	20			16.5				
			CLK low	23			16.5				
	Setup time before CLK↑	Data at A, B, C, D		25			20				
		ENP, ENT	High	35			30				
			Low	25			20				
		SCLR	Low	20			15				
t _{su}			High (inactive)	35			30			ns	
			Low	20			15				
		LOAD	High (inactive)	35			30				
		U/D		35			30				
		ACLR inactive		10			10				
t _h	Hold time after CLK↑ for a	ny input	0			0			ns		
TA	Operating free-air temperature			-55		125	0		70	°C	

SDAS229A - APRIL 1982 - REVISED JANUARY 1995

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		SNS	SN54ALS569A			SN74ALS568A SN74ALS569A			
				MIN	TYP [†]	MAX	MIN	TYP†	MAX		
VIK		$V_{CC} = 4.5 \text{ V},$	$I_1 = -18 \text{ mA}$			-1.5			-1.5	V	
	All outputs	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -0.4 \text{ mA}$	V _{CC} -2	2		V _{CC} -2	2			
Vон	Q outputs	V _{CC} = 4.5 V	$I_{OH} = -1 \text{ mA}$	2.4	3.3					V	
			$I_{OH} = -2.6 \text{ mA}$				2.4	3.2			
	Q outputs	V _{CC} = 4.5 V	I _{OL} = 12 mA		0.25	0.4		0.25	0.4	V	
\/0:			I _{OL} = 24 mA					0.35	0.5		
VOL	CCO and RCO	V _{CC} = 4.5 V	$I_{OL} = 4 \text{ mA}$		0.25	0.4		0.25	0.4		
			$I_{OL} = 8 \text{ mA}$					0.35	0.5		
lozh		$V_{CC} = 5.5 \text{ V},$	$V_0 = 2.7 \text{ V}$			20			20	μΑ	
lozL		$V_{CC} = 5.5 \text{ V},$	$V_0 = 0.4 V$			-20			-20	μΑ	
l _l		$V_{CC} = 5.5 \text{ V},$	V _I = 7 V			0.1			0.1	mA	
lін		$V_{CC} = 5.5 \text{ V},$	V _I = 2.7 V			20			20	μΑ	
I _{IL}		$V_{CC} = 5.5 \text{ V},$	V _I = 0.4 V			-0.2			-0.2	mA	
. +	CCO and RCO	V 55V	V 0.05.V	-15		-70	-15		-70	4	
10‡	Q outputs	V _{CC} = 5.5 V,	$V_0 = 2.25 \text{ V}$	-20		-112	-30		-112	mA	
			Outputs high		16	26		16	26		
ICC		V _{CC} = 5.5 V	Outputs low		20	32		20	32	mA	
			Outputs disabled		20	32		20	32		

[†] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

[‡] The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, I_{OS}.

SN54ALS569A, SN74ALS568A, SN74ALS569A SYNCHRONOUS 4-BIT UP/DOWN DECADE AND BINARY COUNTERS WITH 3-STATE OUTPUTS SDAS229A – APRIL 1982 – REVISED JANUARY 1995

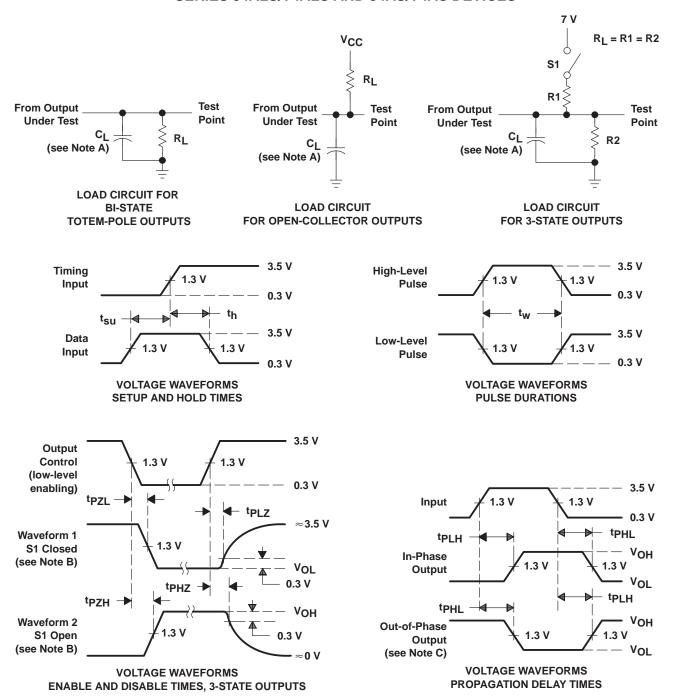
switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	C _I R ² R2	$ V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}, $ $ C_L = 50 \text{ pF}, $ $ R1 = 500 \Omega, $ $ R2 = 500 \Omega, $ $ T_A = \text{MIN to MAX}^{\dagger} $				
			SN54ALS569A		SN74ALS568A SN74ALS569A			
			MIN	MAX	MIN	MAX		
f _{max}	SN74AI	LS568A			20		MHz	
max	'ALS	22		30		IVITZ		
^t PLH	CLK	Any Q	4	21	4	13	ns	
^t PHL	OLK	Any Q	7	19	7	16		
^t PLH	CLK	RCO	12	37	12	28	ns	
^t PHL	OLIV	RCO	10	28	10	19	113	
^t PLH	CLK	cco	5	17	5	13	ns ns ns	
^t PHL			6	30	6	25		
^t PLH	U/D	RCO	9	31	9	23		
^t PHL	0/D		9	33	9	19		
^t PLH	ENT	RCO	6	21	6	15		
^t PHL	LIVI		4	20	4	13		
^t PLH	ENT	CCO	5	18	5	13	ns	
^t PHL	ENI	000	9	32	9	23		
^t PLH	<u>ENP</u>	cco	4	18	4	12	ns	
^t PHL			5	18	5	14		
^t PHL	ACLR	Any Q	9	25	9	20	ns	
^t PZH	ŌĒ	Any Q	6	23	6	18	ns	
^t PZL			6	29	6	24	- 110	
^t PHZ	OE	Any Q	1	12	1	10	ns	
^t PLZ		7 tily Sc	3	29	3	13	110	

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

SDAS229A - APRIL 1982 - REVISED JANUARY 1995

PARAMETER MEASUREMENT INFORMATION SERIES 54ALS/74ALS AND 54AS/74AS DEVICES



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
- D. All input pulses have the following characteristics: $PRR \le 1$ MHz, $t_r = t_f = 2$ ns, duty cycle = 50%.
- E. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms



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